

Search Notes**Application/Control No.**

10/643,858

Examiner

J. Pasterczyk

Applicant(s)/Patent under Reexamination

CHAN ET AL.

Art Unit

1755

SEARCHED

Class	Subclass	Date	Examiner
502	102	4/05	JP
	103		
	117		
	153		
	154		
	155		
526	133		
	134		
	160		
	161		
	172		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Universal search on PALM	4/05	JP

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
502	102, 103 117, 153	8/05	JP
526	133, 134		
	160, 161 172		